


**PRODUCT / PROCESS CHANGE INFORMATION**

**1. PCI basic data**

<b>1.1 Company</b>		STMicroelectronics International N.V
<b>1.2 PCI No.</b>	ADG/22/13261	
<b>1.3 Title of PCI</b>	"STF12N65M5, STP12N65M5, STB8N65M5, STD8N65M5, STF8N65M5 New Rg (Gate input resistance) testing limits - Catania CTM8 8" (Italy)"	
<b>1.4 Product Category</b>	Power MOSFET HV	
<b>1.5 Issue date</b>	2022-02-09	

**2. PCI Team**

<b>2.1 Contact supplier</b>	
<b>2.1.1 Name</b>	KRAUSE INA
<b>2.1.2 Phone</b>	+49 89460062370
<b>2.1.3 Email</b>	ina.krause@st.com
<b>2.2 Change responsibility</b>	
<b>2.2.1 Product Manager</b>	Maurizio GIUDICE
<b>2.1.2 Marketing Manager</b>	Paolo PETRALI
<b>2.1.3 Quality Manager</b>	Vincenzo MILITANO

**3. Change**

<b>3.1 Category</b>	<b>3.2 Type of change</b>	<b>3.3 Manufacturing Location</b>
General (Test Program)	Test limit changes: limits are moved inside datasheet range on parameters (not linked to reliability and SBL) except for wafer for sale	Catania CTM8 8" (Italy)

**4. Description of change**

	<b>Old</b>	<b>New</b>
<b>4.1 Description</b>	"STF12N65M5, STP12N65M5 typ. Rg: 2.5 ? STB8N65M5, STD8N65M5, STF8N65M5 typ. Rg: 4 ? - max. Rg: 6 ?"	"STF12N65M5, STP12N65M5 typ. Rg: 5 ? STB8N65M5, STD8N65M5, STF8N65M5 typ. Rg: 5 ? - max. Rg: 8 ?"
<b>4.2 Anticipated Impact on form,fit, function, quality, reliability or processability?</b>	no impacts	

**5. Reason / motivation for change**

<b>5.1 Motivation</b>	Align the datasheet values with actual production (EWS testing limit)
<b>5.2 Customer Benefit</b>	YIELD IMPROVEMENT

**6. Marking of parts / traceability of change**

<b>6.1 Description</b>	by Q.A. number
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**7. Timing / schedule**

<b>7.1 Date of qualification results</b>	2022-02-07
<b>7.2 Intended start of delivery</b>	2022-03-07
<b>7.3 Qualification sample available?</b>	Upon Request

**8. Qualification / Validation**

<b>8.1 Description</b>			
<b>8.2 Qualification report and qualification results</b>	In progress	<b>Issue Date</b>	

**9. Attachments (additional documentations)**

13261 Public product.pdf  
13261 STx12N65M5 & STx8N65M5 NEW Rg Testing limits.pdf

**10. Affected parts**

<b>10. 1 Current</b>		<b>10.2 New (if applicable)</b>
<b>10.1.1 Customer Part No</b>	<b>10.1.2 Supplier Part No</b>	<b>10.1.2 Supplier Part No</b>
	STD11N65M5	
	STL15N65M5	

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